## Schedule of Internal Academic Rates

**Effective September 1, 2015**

### Secondary Ion Mass Spectrometry (SIMS)
- Cameca IMS-3f with oxygen or caesium source: $140.00/hour
- ION-TOF TOF-SIMS IV with Ga⁺, Cs⁺, SF₅⁺, Ar⁺, O⁺, and C₆₀⁺ beams, 8” sample stage: $140.00/hour

### X-ray Photoelectron Spectroscopy (XPS)
- Kratos AXIS Ultra: $140.00/hour
- Kratos AXIS Nova: $140.00/hour

### Scanning Auger Microscopy (SAM)
- PHI-660 Scanning Auger Microprobe: $140.00/hour

### Scanning Electron Microscopy (SEM) with Energy Dispersive X-ray (EDX) Spectroscopy
- LEO 440 SEM equipped with a Quartz XOne Light Element EDX System: $120.00/hour
- Hitachi S-4500 Field Emission SEM equipped with a Quartz PCI XOne SSD X-ray Analyzer: $120.00/hour
- Hitachi SU3500 Variable Pressure SEM with a Oxford AZtec X-Max50 SDD X-ray Analyzer: $120.00/hour

### Atomic Force Microscopy (AFM)
- PSIA XE-100: $120.00/hour

### Surface Profilometry
- Tencor P-10: $120.00/hour

### Nanomechanical Testing
- Hysitron TI-950 Triboindenter: $120.00/hour

### Laser Raman Spectroscopy
- Renishaw 2000: $140.00/hour

### Fourier Transform Infrared (FTIR) Spectroscopy
- Bruker Tensor II System with Hyperion 2000 Microscope: $140.00/hour

### Optical Microscopy
- Zeiss Axioplan, Zeiss SteREO Discovery.V8, and Wild M3Z: $60.00/hour

### Contact Angle Goniometry
- Ramé-Hart 100: $60.00/hour

### Microindentation Hardness Testing
- Leco LM100: $60.00/sample

### Metallographic Preparation
- Per sample: $70.00/sample

### Etching
- Standard: $70.00/sample
- HF or electrolytic: $140.00/sample

### Priority Service (based on Monday - Friday business hours, excluding weekends and holidays)
- Five business days: 25% surcharge
- Three business days: 50% surcharge
- One business day: 100% surcharge

### Advanced Reporting, Consulting, Data Interpretation, Post-analytical Data Processing, Sample Preparation
- Hourly basis: $140.00/hour